



IMPEDANCE ANALYZER IM7580

Component Measuring Instruments





Measurement time: As fast as 0.5 ms (Analog measurement time)





The IM7580 delivers analog measurement

times as fast as 0.5 ms. In addition, repeatability (variability) has been improved to approximately 1/10 of the legacy model, the 3535.

High-speed, high-stability measurement means you can measure more test pieces in a given amount of time and enjoy better throughput.

HIOKI company overview, new products, environmental considerations and other information are available on our website. ISO 9001 ISO14001 JQA-E-90091

JMI-0216

Measurement capabilities suited to a variety of production lines



For single-frequency pass/fail judgments (LCR mode)



For multiple-frequency pass/fail judgments (Analyzer mode)

Recommended measurements for R&D applications

- · Measurement of frequency characteristics and level characteristics
- · Five-model equivalent circuit analysis

Contact check function (DCR measurement with Hi-Z reject)

The IM7580 can perform contact checks using DCR measurement for components such as inductors, ferrite cores, and commonmode filters. It can also perform contact checks using Hi-Z reject functionality for components such as capacitors.

Both of these capabilities can be combined with a chatter detection check to deliver highly reliable measurement.



For pass/fail judgments based on frequency characteristics (Analyzer mode)



For pass/fail judgments as part of compound tests (Continuous measurement mode)

Space-saving design that fits two instruments into a full-size rack

The IM7580 features a half-rack size form factor that measures 215 W × 200 H × 268 D mm (8.46 W x 7.87 H x 10.55 D inches), allowing two of the instruments to fit side by side in a full-size rack. The instrument also uses a compact test head that measures 61 W \times 55 H \times 24 D mm (2.40 W x 2.17 H x 0.94 D inches).



IM7580 specifications overview

Measurement frequency	Frequency range: 1 MHz to 300 MHz Measurement resolution: 1.0000 MHz to 9.9999 MHz: 100 Hz steps 10.000 MHz to 99.999 MHz: 1 kHz steps 100.00 MHz to 300.00 MHz: 10 kHz steps
Measurement level	-40.0 dBm to +7.0 dBm (4 mV to 1001 mV)
Measurement time	As fast as 0.5 ms (analog measurement time)
Measurement range	100 m Ω to 5 k Ω

Contact check functionality	DCR measurement Hi-Z reject Waveform judgment (chatter detection)
Measurement parameters	Z,Y, θ, Rs, Rp, X, G, B, Cs, Cp, Ls, Lp, D, Q
Analyzer mode	Frequency/level sweep measurement (801 points)
Continuous	LCR mode: 30 conditions
measurement mode	Analyzer mode: 16 conditions
Interfaces	Handler, USB, LAN, GP-IB (optional), RS-232C (optional), USB memory

Test fixtures or probes are not included with the instrument. The Impedance Analyzer IM7580 requires a dedicated test fixture. For

more information, please contact your Hioki distributor.

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Coming soon

(Accessories: Power cord, Instruction manual)



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HIOKI E. E. CORPORATION

HEADQUARTERS:

81 Koizumi, Ueda, Nagano, 386-1192, Japan TEL +81-268-28-0562 FAX +81-268-28-0568 **HIOKI SINGAPORE PTE. LTD.:** http://www.hioki.com / E-mail: os-com@hioki.co.jp TEL +65-6634-7677 FAX +65-663

TEL +91-124-6590210 FAX +91-124-6460113 E-mail: hioki@hioki.in

HIOKI INDIA PRIVATE LIMITED:

HIOKI (Shanghai) SALES & TRADING CO., LTD.:

TEL +86-21-63910090 FAX +86-21-63910360 http://www.hioki.cn / F-mail: info@hioki.com.cn

TEL +65-6634-7677 FAX +65-6634-7477 E-mail: info-sg@hioki.com.sg

HIOKI USA CORPORATION: HIOKI KOREA CO., LTD.: HUN KORA CO., HIN HON COMPANY AND A CONTROL AND A CONTROL

All information correct as of Aug. 28, 2014. All specifications are subject to change without notice.

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